

## Fault-Tolerant Computer Systems

### Welcome to Lecture 3

Reliability modeling

## Outline Lecture 2

- Basic probability theory
- Reliability
- MTTF = Mean Time To Failure
- Reliability block diagrams
- Series systems
- Parallel systems
- TMR
- m-of-n systems

## Motivation

We use probability theory to gain insight into the properties of redundancy configurations and architectures of fault-tolerant systems.

Probability theory allow us to quantitatively assess the dependability of a fault-tolerant system in terms of

- **Reliability**
- **Availability**, and
- **Safety**

## Concepts in Probability

Let  $X$  denote the lifetime for a component.

$$F(t) = P(X \leq t) \quad \text{Distribution function}$$

$$R(t) = 1 - F(t) = P(X > t) \quad \text{Reliability function}$$

$$f(t) = \frac{d}{dt}F(t) \quad \text{Probability density function}$$

## The exponential distribution

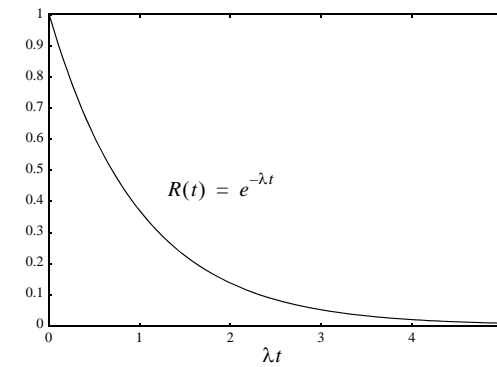
$$F(t) = 1 - e^{-\lambda t} \quad \text{Distribution function}$$

$$R(t) = e^{-\lambda t} \quad \text{Reliability function}$$

$$f(t) = \lambda e^{-\lambda t} \quad \text{Probability density function}$$

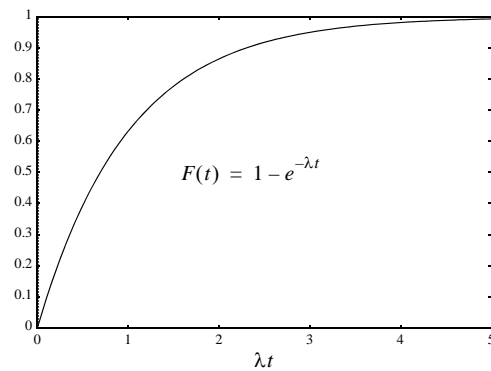
$\lambda$  is the failure rate for the component and  $t$  is the time

## Reliability function



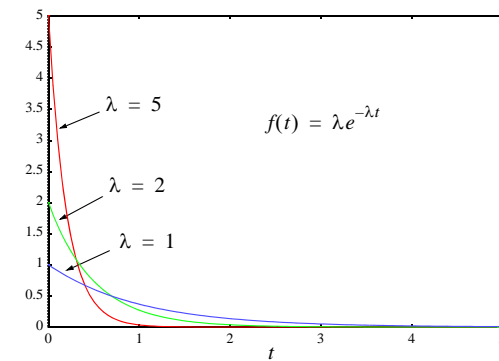
The exponential distribution

## Distribution function



The exponential distribution

## Probability density function



The exponential distribution

## Failure rate function

$$h(t) = \frac{f(t)}{R(t)}$$

The exponential distribution has a constant failure rate:

$$h(t) = \frac{f(t)}{R(t)} = \frac{\lambda e^{-\lambda t}}{e^{-\lambda t}} = \lambda$$

## The Bathtub Curve

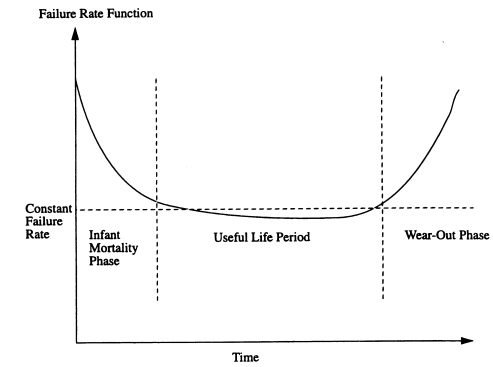


Figure 1.25: Illustration of the bathtub curve relationship. (From Barry W. Johnson, *Design and Analysis of Fault-Tolerant Digital Systems*, Addison-Wesley Publishing Company, Reading, Mass., 1989, p. 173.)

## Mean Time To Failure (MTTF)

MTTF = expected time to failure

$$MTTF = \int_0^{\infty} R(t) dt$$

Proof of  $MTTF = \int_0^{\infty} R(t) dt$

Let  $X$  denote the lifetime for the component

$$\begin{aligned} MTTF &= E[X] = \int_0^{\infty} t \cdot f(t) dt = - \int_0^{\infty} t \cdot R'(t) dt \\ &= - t \cdot R(t) \Big|_0^{\infty} + \int_0^{\infty} R(t) dt = \int_0^{\infty} R(t) dt \end{aligned}$$

## MTTF for the exponential distribution

$$MTTF = E[X] = \int_0^{\infty} e^{-\lambda t} dt = -\frac{e^{-\lambda t}}{\lambda} \Bigg|_0^{\infty} = \frac{1}{\lambda}$$

## Example

What is the probability that a component with an exponentially distributed life-time will survive the expected lifetime?

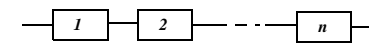
$$R\left(t = \frac{1}{\lambda}\right) = e^{-\left(\lambda \cdot \frac{1}{\lambda}\right)} = e^{-1} = 0,37$$

**Only 37% of the components survive the expected lifetime.**

## Reliability Block Diagrams

- Series systems
- Parallel systems
- m-of-n systems

## Series system with $n$ components



Reliability block diagram

The reliability of the series system is

$$R_{serie} = R_1 \cdot R_2 \cdot \dots \cdot R_n = \prod_{i=1}^n R_i$$

*iff* the component failures are independent.

## Reliability of a series system

For the components  $i = 1, 2, \dots, n$  we define the events

$A_i = \text{'component } i \text{ works'}$

We denote the probability that the component  $i$  works

$$P(A_i) = R_i$$

If the events  $A_i$  are independent, the reliability of the series system is

$$\begin{aligned} R_{\text{serie}} &= P(\text{'The system works'}) = P(A_1 \cap A_2 \cap \dots \cap A_n) \\ &= P(A_1) \cdot P(A_2) \cdot \dots \cdot P(A_n) \\ &= \prod_{i=1}^n R_i \end{aligned}$$

## Series system of components with exponentially distributed lifetimes

$$R_i = e^{-\lambda_i \cdot t}$$

$$R_{\text{serie}} = \prod_{i=1}^n e^{-\lambda_i \cdot t} = e^{-\sum_{i=1}^n \lambda_i \cdot t}$$

The failure rate of the series system is equal to the sum of the component failure rates.

**This is called the “parts count” principle.**

## MTTF for a series system

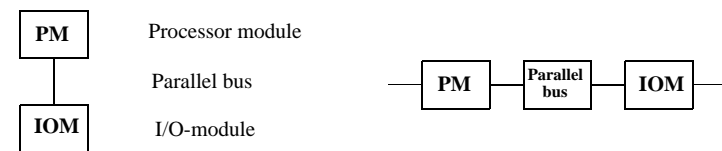
The failure rate for the series system is

$$\lambda_{\text{sys}} = \sum_{i=1}^n \lambda_i$$

The MTTF is then

$$MTTF = \frac{1}{\lambda_{\text{sys}}} = \frac{1}{\sum_{i=1}^n \lambda_i}$$

## Example 1 - Series system



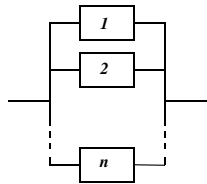
System architecture

Reliability block diagram

The reliability of the system is:

$$R_{\text{sys}} = e^{-(\lambda_{\text{PM}} + \lambda_{\text{Parallelbus}} + \lambda_{\text{IOM}}) \cdot t}$$

## Parallel system with $n$ components



Reliability block diagram

The reliability of a parallel system is

$$R_{par} = 1 - F_{par} = 1 - \prod_{i=1}^n F_i = 1 - \prod_{i=1}^n (1 - R_i)$$

## Reliability of a parallel system

For the components  $i = 1, 2, \dots, n$  we define the events

$\bar{A}_i =$  'component  $i$  has failed'

The probability that component  $i$  is broken can then be expressed as

$$P(\bar{A}_i) = F_i$$

If the events  $\bar{A}_i$  are independent, the reliability for the parallel system is

$$\begin{aligned} R_{par} &= 1 - P(\text{'The system has failed'}) = 1 - P(\bar{A}_1 \cap \bar{A}_2 \cap \dots \cap \bar{A}_n) \\ &= 1 - P(\bar{A}_1) \cdot P(\bar{A}_2) \cdot \dots \cdot P(\bar{A}_n) \\ &= 1 - \prod_{i=1}^n F_i = 1 - \prod_{i=1}^n (1 - R_i) \end{aligned}$$

## Examples

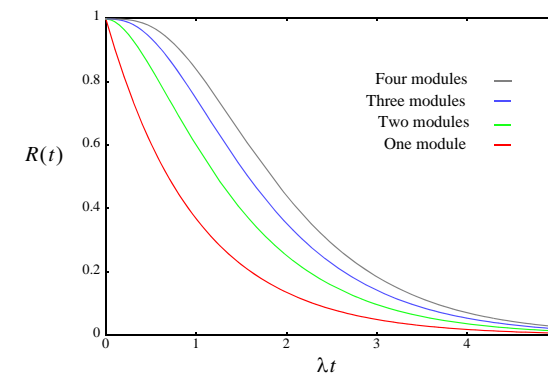
The reliability for parallel systems consisting of 2, 3 or 4 identical components with exponentially distributed lifetimes are:

$$2 \text{ modules: } R_{2p} = 1 - (1 - R_1)^2 = 1 - (1 - e^{-\lambda t})^2 = 2e^{-\lambda t} - e^{-2\lambda t}$$

$$3 \text{ modules: } R_{3p} = 1 - (1 - R_1)^3 = 1 - (1 - e^{-\lambda t})^3 = 3e^{-\lambda t} - 3e^{-2\lambda t} + e^{-3\lambda t}$$

$$4 \text{ modules: } R_{4p} = 1 - (1 - R_1)^4 = 1 - (1 - e^{-\lambda t})^4 = 4e^{-\lambda t} - 6e^{-2\lambda t} + 4e^{-3\lambda t} - e^{-4\lambda t}$$

## The reliability for parallel systems



## MTTF for a parallel system with $n$ components

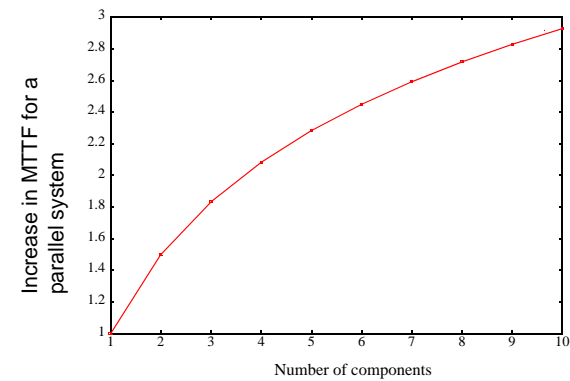
Let  $X$  denote the lifetime of the system

$$MTTF = E[X] = \int_0^{\infty} R(t) dt = \int_0^{\infty} 1 - (1 - e^{-\lambda t})^n dt$$

Make the substitution  $u = 1 - e^{-\lambda t}$ ,  $dt = \frac{1}{\lambda(1-u)} \cdot du$ . We then obtain

$$\begin{aligned} MTTF &= \frac{1}{\lambda} \cdot \int_0^1 \frac{1-u^n}{1-u} du = \frac{1}{\lambda} \cdot \int_0^1 \sum_{i=1}^n u^{i-1} du = \frac{1}{\lambda} \cdot \sum_{i=1}^n \frac{u^i}{i} \Big|_0^1 \\ &= \frac{1}{\lambda} \cdot \sum_{i=1}^n \frac{1}{i} \approx \frac{1}{\lambda} \cdot (\ln(n) + 0,57722) \end{aligned}$$

## MTTF for parallel systems

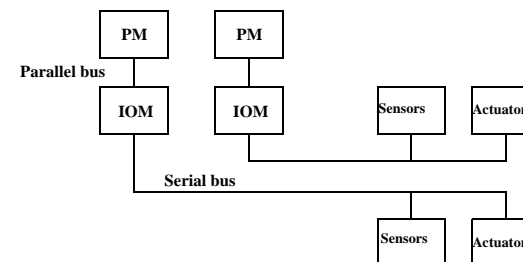


## Example - MTTF for parallel systems

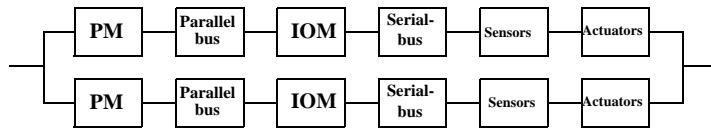
What is the MTTF for a parallel system consisting of 4 components if the MTTF for one component is  $\frac{1}{\lambda}$ ?

$$MTTF = \frac{1}{\lambda} \cdot \sum_{i=1}^4 \frac{1}{i} = \frac{1}{\lambda} \cdot \left(1 + \frac{1}{2} + \frac{1}{3} + \frac{1}{4}\right) = \frac{25}{12} \cdot \frac{1}{\lambda}$$

## Example 2, A parallel system



### Example 2, parallel system (cont'd.)



Reliability block diagram

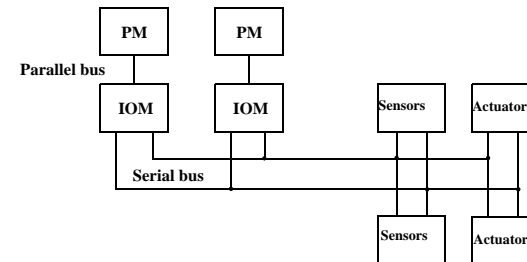
The system reliability is:

$$\lambda_{subsys} = \lambda_{PM} + \lambda_{parallelbus} + \lambda_{IOM} + \lambda_{serialbus} + \lambda_{sensors} + \lambda_{actuators}$$

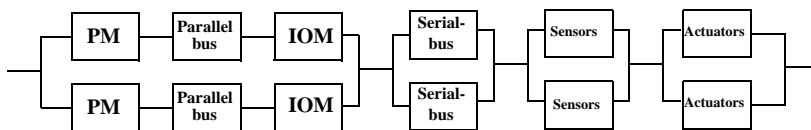
$$R_{subsys} = e^{-\lambda_{subsys} \cdot t}$$

$$\begin{aligned} R_{sys} &= 1 - (1 - R_{subsys})^2 = 1 - (1 - 2 \cdot R_{subsys} + R_{subsys}^2) = 2 \cdot R_{subsys} - R_{subsys}^2 \\ &= 2e^{-\lambda_{subsys} \cdot t} - e^{-2\lambda_{subsys} \cdot t} \end{aligned}$$

### Example 3



### Example 3 (cont'd.)



Reliability block diagram

The reliability function

$$\lambda_1 = \lambda_{PM} + \lambda_{parallelbus} + \lambda_{IOM}$$

$$\begin{aligned} R_{sys} &= (1 - (1 - e^{-\lambda_1 \cdot t})^2) \cdot (1 - (1 - e^{-\lambda_{serialbus} \cdot t})^2) \cdot (1 - (1 - e^{-\lambda_{sensors} \cdot t})^2) \cdot \\ &\quad (1 - (1 - e^{-\lambda_{actuators} \cdot t})^2) \end{aligned}$$

### Example m-of-n systems

Derive the reliability for a TMR system (= 2-of-3 system).

Let  $R$  denote the reliability for one module.

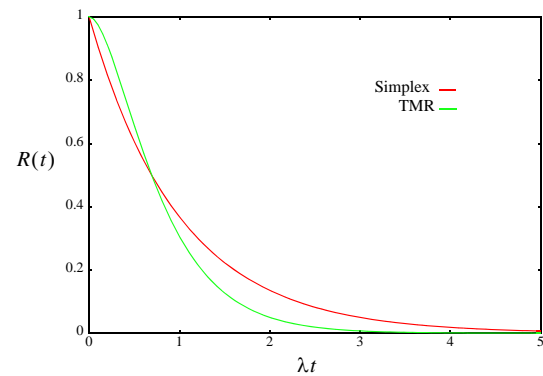
$$\begin{aligned} R_{TMR} &= P(\text{'all modules are functioning'}) + P(\text{'exactly two modules are functioning'}) \\ &= R^3 + 3R^2 \cdot (1 - R) = 3R^2 - 2R^3 \end{aligned}$$

If the lifetimes of the modules are exponentially distributed, we obtain:

$$\begin{aligned} R &= e^{-\lambda t} \\ R_{TMR} &= 3e^{-2\lambda t} - 2e^{-3\lambda t} \end{aligned}$$



## Reliability for TMR and Simplex systems



## MTTF for a TMR-system

$$\begin{aligned}
 MTTF &= \int_0^{\infty} R_{TMR} dt = \int_0^{\infty} (3e^{-2\lambda t} - 2e^{-3\lambda t}) dt = \\
 &= -\frac{3}{2\lambda} \cdot e^{-2\lambda t} \Big|_0^{\infty} + \frac{2}{3\lambda} \cdot e^{-3\lambda t} \Big|_0^{\infty} = \\
 &= \frac{3}{2\lambda} - \frac{2}{3\lambda} = \frac{5}{6} \cdot \frac{1}{\lambda}
 \end{aligned}$$

The MTTF for the TMR-system is only 5/6 of the MTTF for the simplex system!

## *m*-*av*-*n* systems (cont'd.)

In general, we can write the reliability for an *m*-*of*-*n* system as

$$R_{m\text{-of-}n} = \sum_{i=m}^n \binom{n}{i} \cdot R^i (1-R)^{n-i}$$

## *m*-*of*-*n* systems (cont'd)

Examples:

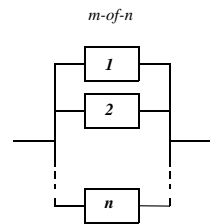
2-of-3 system

$$R_{2\text{-of-}3} = \sum_{i=2}^3 \binom{3}{i} \cdot R^i (1-R)^{3-i} = \binom{3}{2} \cdot R^2 (1-R) + \binom{3}{3} \cdot R^3 = 3R^2 - 2R^3$$

2-of-4 system:

$$\begin{aligned}
 R_{2\text{-of-}4} &= \sum_{i=2}^4 \binom{4}{i} \cdot R^i (1-R)^{4-i} = \binom{4}{2} \cdot R^2 (1-R)^2 + \binom{4}{3} \cdot R^3 (1-R) + \binom{4}{4} \cdot R^4 \\
 &= 6R^2(1-R)^2 + 4R^3(1-R) + R^4 = 6R^2 - 8R^3 + 3R^4
 \end{aligned}$$

## Reliability block diagram for $m$ -of- $n$ systems



Reliability block diagram

## Overview of Lecture 4

- Case study: Ariane 501 disaster
- Software redundancy

Read *before* the lecture:

Course book: Section 6.1, 6.2 (software faults), 6.3, 6.6

Reprints:

1. Report on Ariane 501 failure (important!)
2. A Large Scale Experiment in N-version Programming (Skip Section 4, Model of Independence)
3. An Evaluation of Software Fault Tolerance in a Practical System (skip Section 5, Analysis of Results)